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 Meet or Exceed the Requirements of ANSI EIA/TIA-232-E and ITU Recommendation 	-	PACKAGE VIEW) 14 V _{CC} 13 4A 12 4 CONT
 V.28 Low Supply Current 420 μA Typ Preset On-Chip Input Noise Filter Built-in Input Hysteresis Response and Threshold Control Inputs Push-Pull Outputs 	1A 1 1 CONT 2 1Y 3 2A 4 2 CONT 5 2Y 6 OND 7	13] 4A 12] 4 CONT 11] 4Y 10] 3A 9] 3 CONT
 Functionally Interchangeable and Pin Compatible With Texas Instruments SN75189/SN75189A, Motorola MC1489/MC1489A, and National Semiconductor DS14C88A 	GND[<mark>]</mark> 7	8 3Y

description

The SN75C189 and SN75C189A are low-power bipolar quadruple line receivers that are used to interface data terminal equipment (DTE) with data circuit-terminating equipment (DCE). These devices have been designed to conform with ANSI Standard EIA/TIA-232-E.

The SN75C189 has a 0.33 V typical hysteresis compared with 0.97 V for the SN75C189A. Each receiver has provision for adjustment of the overall input threshold levels. This is achieved by choosing external series resistors and voltages to provide bias levels for the response control pins. The output is in the high logic state if the input is left open circuited or shorted to ground.

These devices have an on-chip filter that rejects input pulses of shorter than 1-µs minimum duration. An external capacitor may be connected from the control pins to ground to provide further input noise filtering for each receiver.

The SN75C189 and SN75C189A have been designed using low-power techniques in a bipolar technology. In most applications, these receivers will interface to single inputs of peripheral devices such as UARTs, ACEs, or microprocessors. By using sampling, such peripheral devices are usually insensitive to the transition times of the input signals. If this is not the case or for other uses, it is recommended that the SN75C189A and SN75C189A outputs be buffered by single Schmitt input gates or single gates of the HCMOS, ALS, or 74F logic families.

The SN75C189 and SN75C189A are characterized for operation from 0°C to 70°C.



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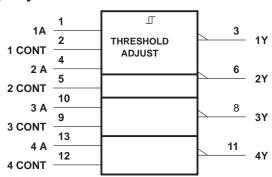
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



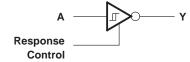
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logic symbol[†]

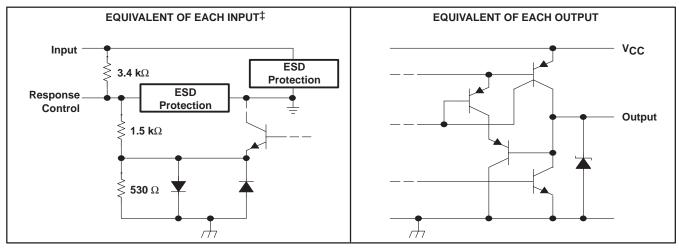


logic diagram (each receiver)



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

schematic of inputs and outputs



[‡] All resistor values shown are nominal.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)§

Supply voltage, V _{CC} (see Note 1)	
Input voltage range, V _I	-30 V to 30 V
Output voltage range, V _O	-0.3 V to V _{CC} + 0.3 V
Continuous total dissipation	See Dissipation Rating Table
Operating free-air temperature range, T _A : SN75C189, SN75C189A	0°C to 70°C
Storage temperature range, T _{stg}	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	
§ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the de	
functional operation of the device at these or any other conditions beyond those indicated under "reco implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliab	

NOTE 1: All voltages are with respect to the network ground terminal.



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DISSIPATION RATING TABLE							
PACKAGE $T_A = 25^{\circ}C$ DERATING FACTOR $T_A = 7$ POWER RATINGABOVE $T_A = 25^{\circ}C$ POWER I							
D	950 mW	7.6 mW/°C	608 mW				
DB	525 mW	4.2 mW/°C	336 mW				
N	1150 mW	9.2 mW/°C	736 mW				
NS	500 mW	4.0 mW/°C	320 mW				

recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V _{CC}	4.5	5	6	V
Input voltage, VI (see Note 2)	-25		25	V
High-level output current, I _{OH}			-3.2	mA
Low-level output current, IOL			3.2	mA
Response control current			±1	mA
Operating free-air temperature, T _A	0		70	°C

NOTE 2: The algebraic convention, where the more positive (less negative) limit is designated as maximum, is used in this data sheet for logic levels only, e.g., if –10 V is a maximum, the typical value is a more negative voltage.

electrical characteristics over recommended free-air temperature range, V_{CC} = 5 V $\pm 10\%$ (unless otherwise noted) (see Note 3)

	PARAMETER		TEST CONDI	TIONS	MIN	TYP†	MAX	UNIT
V	Depitive going input threshold voltage	'C189	See Figure 1		1		1.5	V
VIT+	Positive-going input threshold voltage	'C189A			1.6		2.25	
	Negotive going input threaded values	'C189	See Figure 1		0.75		1.25	V
VIT-	Negative-going input threshold voltage	'C189A			0.75	1	1.25	
N/.	$ a_{1} \rangle \langle a_{2} \rangle \langle a_$	'C189		0.15	0.33		V	
V _{hys}	Input hysteresis voltage (V _{IT+} – V _{IT} –)	'C189A	See Figure 1		0.65	0.97		
V _{OH} High-level output voltage		$V_{CC} = 4.5 V \text{ to } 6 V,$ $I_{OH} = -20 \ \mu\text{A}$	V I = 0.75 V,	3.5			V	
		$V_{CC} = 4.5 V \text{ to } 6 V,$ $I_{OH} = -3.2 \text{ mA}$	V _I = 0.75 V,	2.5				
VOL	Low-level output voltage		$V_{CC} = 4.5 V \text{ to } 6 V,$ $I_{OL} = 3.2 \text{ mA}$	V _I = 3 V,			0.4	V
	Lick lovel input ourrent	See Figure 2	V _I = 25 V	3.6		8.3	A	
ЧΗ	High-level input current		V _I = 3 V	0.43		1	mA	
		$V_{I} = -$	See Figure 2	V _I = -25 V -3	-3.6		-8.3	
IIL	Low-level input current			$V_{I} = -3 V$	-0.43		-1	mA
los	Short-circuit output current		See Figure 3				-35	mA
ICC	Supply current		V _I = 5 V, See Figure 2	No load,		420	700	μΑ

[†] All typical values are at $T_A = 25^{\circ}C$.

NOTE 3: All characteristics are measured with response control terminal open.



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switching characteristics, V_{CC} = 5 V $\pm 10\%,$ T_A = 25°C

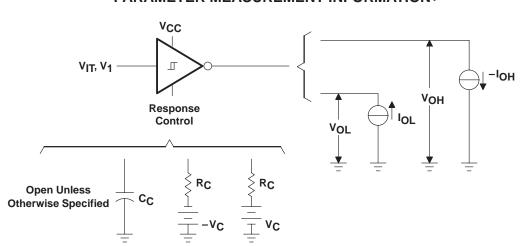
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
^t PLH	Propagation delay time, low- to high-level output				6	μs
^t PHL	Propagation delay time, high- to low-level output	$R_L = 5 k\Omega$, $C_L = 50 pF$, See Figure 4			6	μs
t _{TLH}	Transition time, low- to high-level output †				500	ns
^t THL	Transition time, high- to low-level $output^\dagger$				300	ns
tw(N)	Duration of longest pulse rejected as noise \ddagger		1		6	μs

[†] Measured between 10% and 90% points of output waveform.

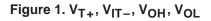
[‡] The receiver ignores any positive- or negative-going pulse that is less than the minimum value of $t_{W(N)}$ and accepts any positive- or negative-going pulse greater than the maximum of $t_{W(N)}$.



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PARAMETER MEASUREMENT INFORMATION[†]



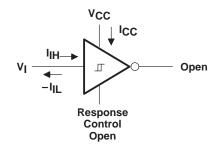


Figure 2. I_{IH} , I_{IL} , I_{CC}

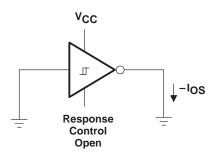
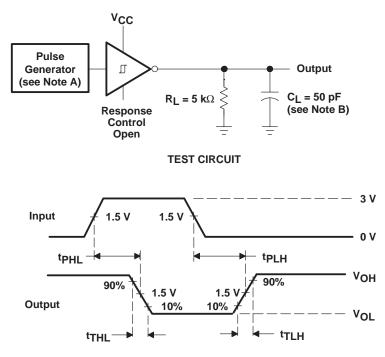


Figure 3. IOS

[†] Arrows indicate actual direction of current flow. Current into a terminal is a positive value.



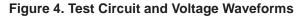
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PARAMETER MEASUREMENT INFORMATION

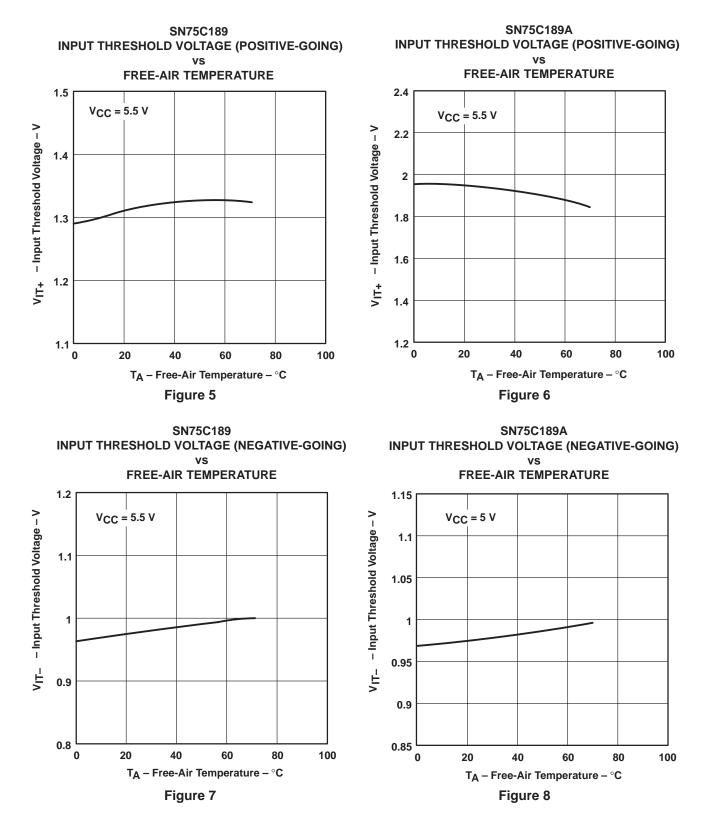
VOLTAGE WAVEFORMS

- NOTES: A. The pulse generator has the following characteristics: $Z_O = 50 \ \Omega$, $t_W = 25 \ \mu$ s.
 - B. CL includes probe and jig capacitances.



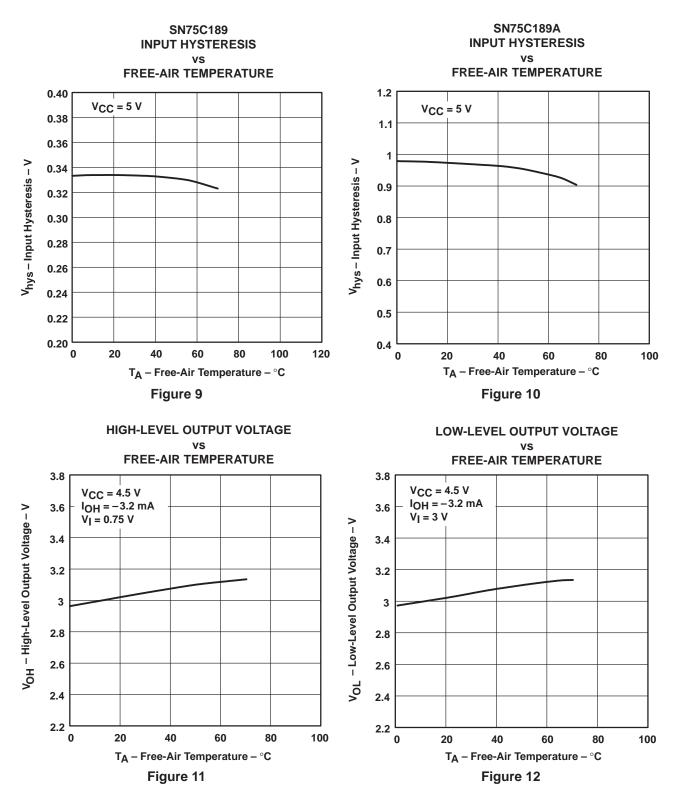


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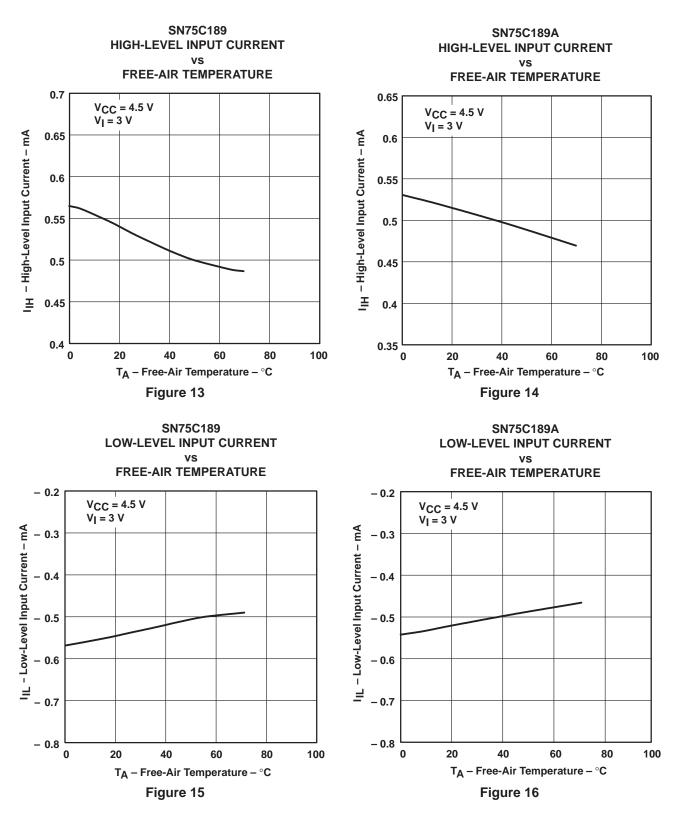


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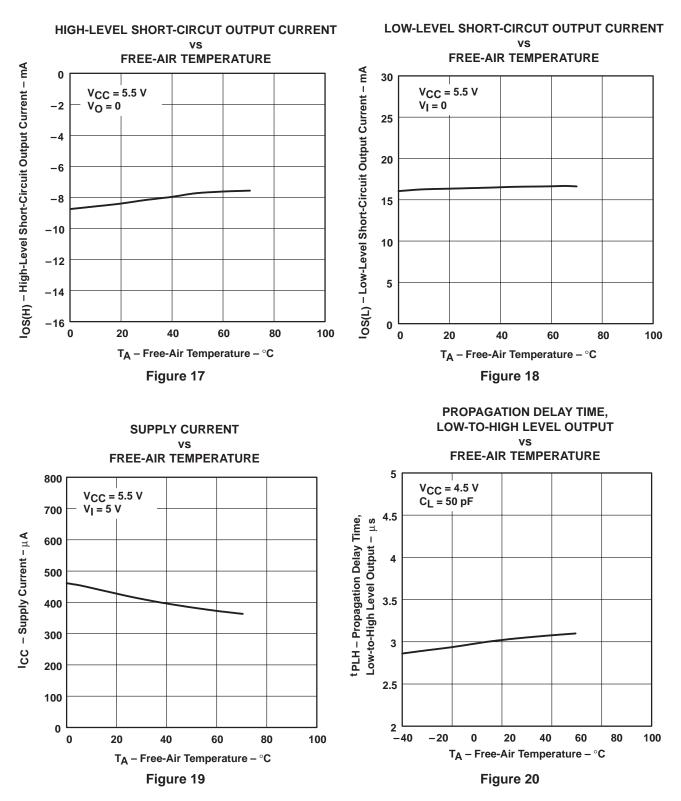


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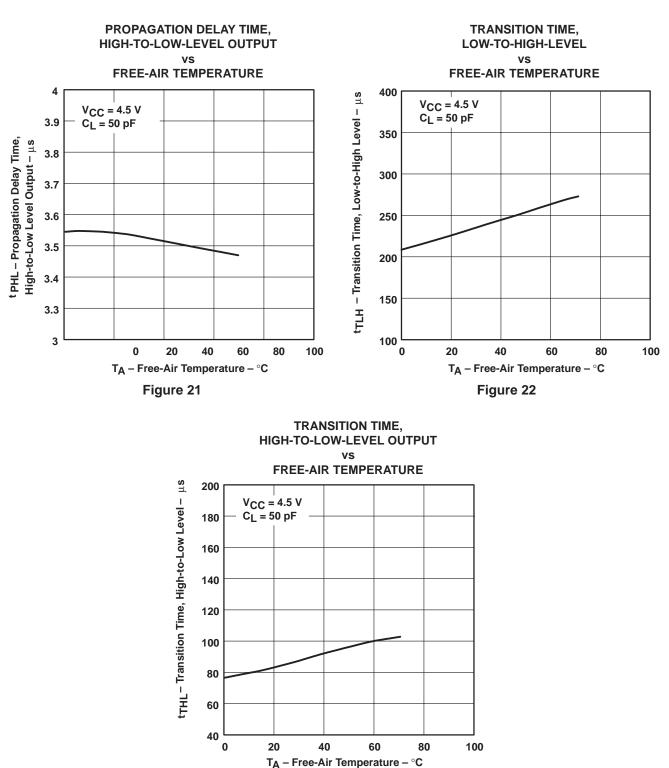


Figure 23



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